

Problem #1

Case 1: Long structure (600 nm)

100 nm: Highly doped ($5 \times 10^{17} \text{ cm}^{-3}$)

400 nm: Lowly doped ($2 \times 10^{15} \text{ cm}^{-3}$)

100 nm: Highly doped ($5 \times 10^{17} \text{ cm}^{-3}$)

Case 2: Short structure (120 nm)

40 nm: Highly doped ($5 \times 10^{19} \text{ cm}^{-3}$)

40 nm: Lowly doped ($2 \times 10^{17} \text{ cm}^{-3}$)

40 nm: Highly doped ($5 \times 10^{19} \text{ cm}^{-3}$)

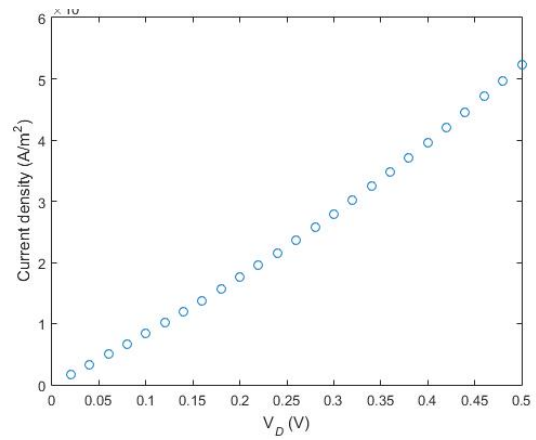
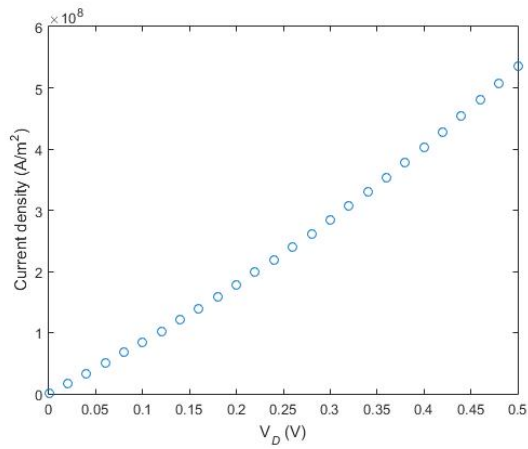


Figure 1 Current density of doped silicon. (1) Case 1: Long structure (2) Case 2: Short structure.

Problem #2 Series resistor-capacitor circuits

$$C = 5 \text{ pF}$$

$$R = 2 \text{ M}\Omega$$

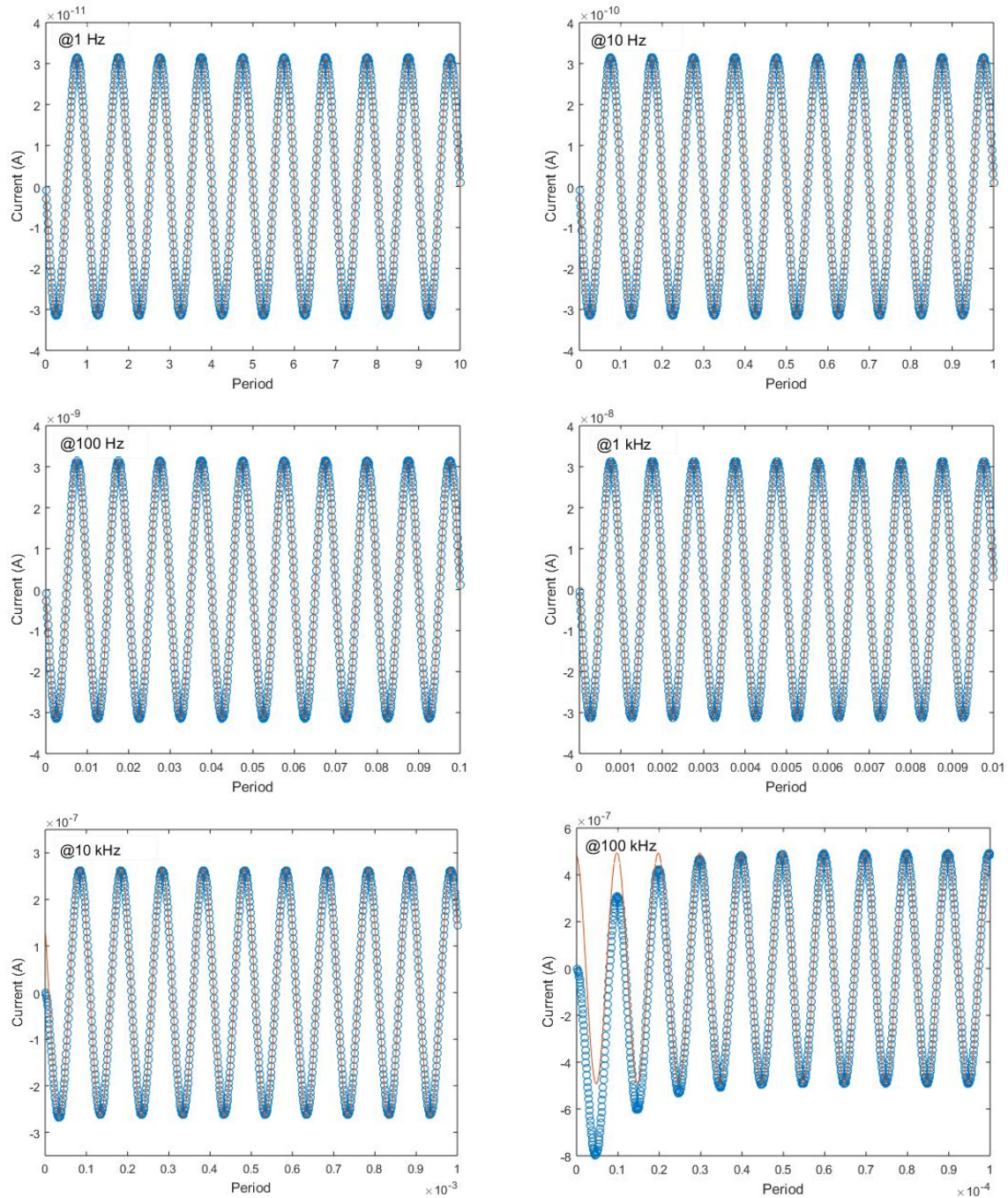


Figure 2 Numerical analysis of the series resistor-capacitor circuits at various AC frequency. The solid lines are exact solution and blue symbols are numerical results.